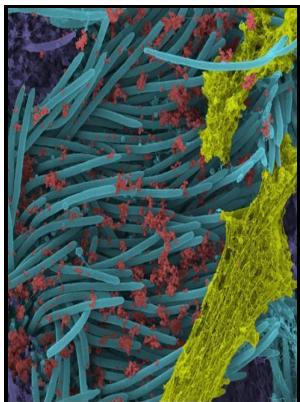


Scanning electron microscopy 1969 - proceedings of the second annual Scanning Electron Microscope Symposium held at the IIT Research Institute, Chicago, Illinois, U.S.A. April 29- May 1, 1969

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Scanning electron microscopy 1969 : proceedings of the 2nd Annual Scanning Electron Microscope Symposium, held at IIT Research Institute, Chicago, Illinois, April 29

In scientific journals one often wonders what happened between the two contending parties that could have delayed publication of a paper, sometimes by as much as a year. There are also papers dealing with photoemission electron microscopy and scanning transmission electron microscopy STEM, two techniques which have only recently become available in commercial instruments.

Scanning electron microscopy 1970 : proceedings of the 3rd Annual Scanning Electron Microscope Symposium, held at IIT Research Institute, Chicago, Illinois, April 28

IIT Research Institute, Chicago, Illinois 60616, 1976.

Scanning electron microscopy 1968 : proceedings of the Symposium on the Scanning Electron Microscope

Other workshops at the meeting concerned studies of particulate matter, and the use of the SEM in microelectronics device fabrication and quality control, and several papers dealing with subjects under these general titles are published here.

Scanning electron microscopy 1969 : proceedings of the 2nd Annual Scanning Electron Microscope Symposium, held at IIT Research Institute, Chicago, Illinois, April 29

In addition to research articles, this volume contains the texts of tutorials given at the meeting, and extensive bibliographies on cathodolumines-

cence and forensic applications of the SEM. This is a most useful reference volume to researchers using the scan- ning electron microscope and at the price is somewhat of a bargain by today's standards.

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